

March 2007

FDS8813NZ N-Channel PowerTrench[®] MOSFET 30V, 18.5A, 4.5mΩ

Features

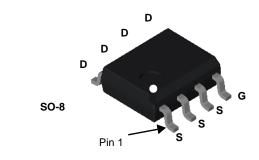
- Max $r_{DS(on)}$ = 4.5m Ω at V_{GS} = 10V, I_D = 18.5A
- Max $r_{DS(on)}$ = 6.0m Ω at V_{GS} = 4.5V, I_D =16A
- HBM ESD protection level of 5.6kV typical (note 3)
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability
- RoHS compliant

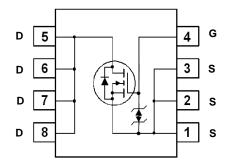


General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench[®] process that has been especially tailored to minimize the on-state resistance.

This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.





MOSFET Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Units		
V _{DS}	Drain to Source Voltage		30	V	
V _{GS}	Gate to Source Voltage		±20	V	
I _D	Drain Current -Continuous	(Note 1a)	18.5	Α	
	-Pulsed		74		
E _{AS}	Single Pulse Avalanche Energy	(Note 4)	337	mJ	
P _D	Power Dissipation	(Note 1a)	2.5	w	
	Power Dissipation	(Note 1b)	1.0	VV	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C	

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	(Note 1)	25	
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient	(Note 1b)	125	

Package Marking and Ordering Information

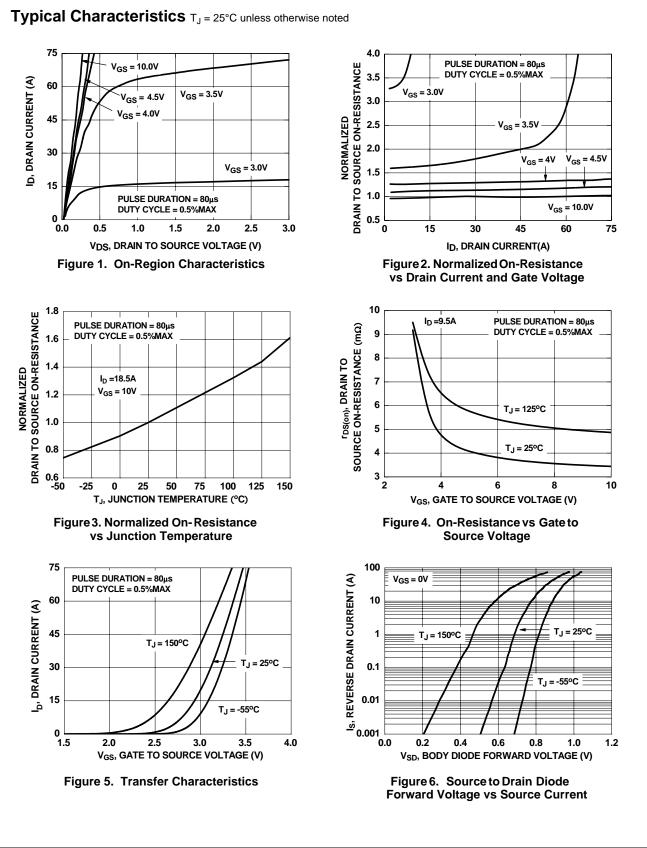
Device Marking	Device	Reel Size	Tape Width	Quantity
FDS8813NZ	FDS8813NZ	13"	12mm	2500 units

	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_{D} = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C		20		mV/°C
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 24V, V_{GS} = 0V$			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±10	μA
	Icteristics (Note 2)		ł	-	1	
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1	1.8	3	V
	Gate to Source Threshold Voltage		•	1.0	Ū	•
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Temperature Coefficient	$I_D = 250 \mu A$, referenced to $25^{\circ}C$		-6		mV/°C
		$V_{GS} = 10V, I_D = 18.5A$		3.8	4.5	
r _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 4.5V, I _D = 16A		4.7	6.0	mΩ
· DS(01)		$V_{GS} = 10V, I_D = 18.5A, T_J = 125^{\circ}C$		5.1	6.6	
9 _{FS}	Forward Transconductance	$V_{DS} = 5V, I_{D} = 18.5A$		74		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance			3115	4145	pF
C _{oss}	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$		580	775	pF
C _{rss}	Reverse Transfer Capacitance	f = 1MHz		345	520	pF
R _g	Gate Resistance	f = 1MHz		1.8	520	Ω
×		1 - 11112		1.0		22
Switching	g Characteristics					T
t _{d(on)}	Turn-On Delay Time	V _{DD} = 15V, I _D = 18.5A		13	24	ns
t _r	Rise Time	$V_{DD} = 15V, T_D = 18.5A$ 		8	16	ns
t _{d(off)}	Turn-Off Delay Time	VGS = 100, NGEN = 012		39	63	ns
t _f	Fall Time			7	14	ns
Qg	Total Gate Charge	$V_{GS} = 0V$ to $10V$ $V_{DD} = 15V$		55	76	nC
Qg	Total Gate Charge	$V_{GS} = 0V \text{ to } 5V$ $I_D = 18.5A$		28	40	nC
Q _{gs}	Gate to Source Charge			9		nC
Q _{gd}	Gate to Drain "Miller" Charge			10		nC
	urce Diode Characteristics					
Drain-Sol		$V_{GS} = 0V, I_S = 2.1A$ (Note 2)		0.7	1.2	V
	Source to Drain Diode Forward Voltage					
V _{SD} t _{rr}	Reverse Recovery Time	$I_{\rm F}$ = 18.5A, di/dt = 100A/µs		32	47	ns

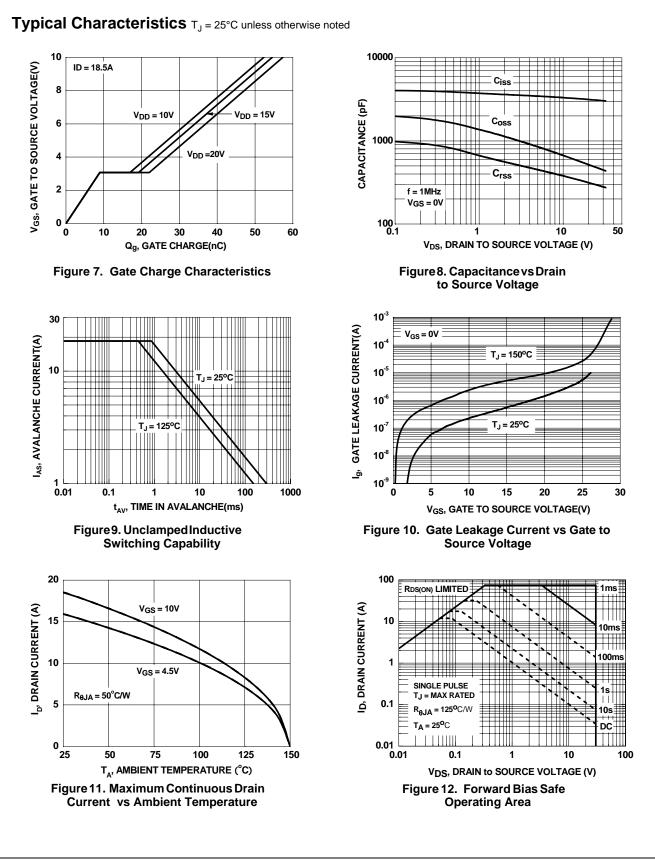
Pulse Test: Pulse Width < 300 us, Duty Cycle < 2%.
The diode connected between the gate and source serves only as protection against ESD . No gate overvoltage rating is implied.
Starting T_J = 25°C, L = 3mH, I_{AS} = 15A, V_{DD} = 30V, V_{GS} = 10V.

FDS8813NZ Rev.C

www.fairchildsemi.com

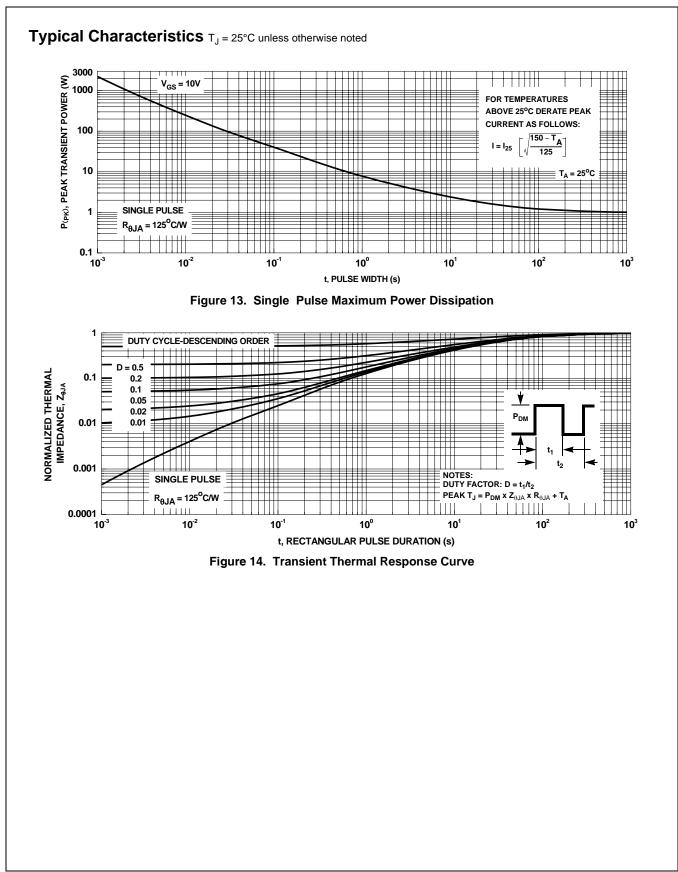


3



www.fairchildsemi.com

FDS8813NZ N-Channel PowerTrench[®] MOSFET



FDS8813NZ N-Channel PowerTrench[®] MOSFET



SEMICONDUCTOR

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx® Across the board. Around the world.™ ActiveArray™ Bottomless™ Build it Now™ CoolFET™ CROSSVOLT™ CTL™ Current Transfer Logic™ DOME™ E²CMOS™ EcoSPARK[®] EnSigna™ FACT Quiet Series™ FACT® $\mathsf{FAST}^{\mathbb{R}}$ FASTr™ FPS™ **FRFET**[®] GlobalOptoisolator™ GTO™

HiSeC™ i-Lo™ ImpliedDisconnect[™] IntelliMAX™ **ISOPLANAR™** MICROCOUPLER™ MicroPak™ MICROWIRE™ MSX™ MSXPro™ OCX™ OCXPro™ **OPTOLOGIC**[®] **OPTOPLANAR[®]** PACMAN™ POP™ Power220[®] Power247[®] PowerEdae™ PowerSaver™ PowerTrench®

QFET[®] QS™ QT Optoelectronics™ Quiet Series[™] RapidConfigure™ RapidConnect™ ScalarPump™ SMART START™ SPM® STEALTH™ SuperFET™ SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SyncFET™ TCM™ The Power Franchise[®] TM TinvBoost™ TinyBuck™

Programmable Active Droop[™] TinyLogic[®] **TINYOPTO™** TinyPower™ TinyWire™ TruTranslation™ µSerDes™ UHC® UniFET™ VCX™ Wire™

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, DEFORMED SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein: 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when the subscription of properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.

2. A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild Semiconductor. The datasheet is printed for reference information only.